Protected Power MOSFET

2.6 A, 52 V, N-Channel, Logic Level, Clamped MOSFET w/ ESD Protection

Benefits

- High Energy Capability for Inductive Loads
- Low Switching Noise Generation

Features

- Diode Clamp Between Gate and Source
- ESD Protection HBM 5000 V
- Active Over-Voltage Gate to Drain Clamp
- Scalable to Lower or Higher R_{DS(on)}
- Internal Series Gate Resistance
- These are Pb-Free Devices

Applications

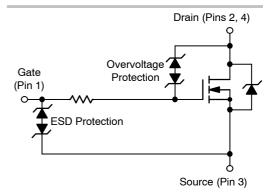
- Automotive and Industrial Markets:
 Solenoid Drivers, Lamp Drivers, Small Motor Drivers
- NCV Prefix for Automotive and Other Applications Requiring Site and Control Changes

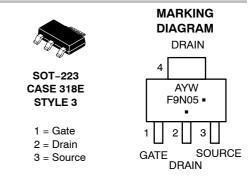


ON Semiconductor®

http://onsemi.com

V _{DSS} (Clamped)	R _{DS(ON)} TYP	I _D MAX
52 V	95 mΩ @ 10 V	2.6 A





A = Assembly Location

Y = Year

W = Work Week ■ Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NCV8440STT1G	SOT-223 (Pb-Free)	1000/Tape & Reel
NCV8440STT3G	SOT-223 (Pb-Free)	4000/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

1

$\textbf{MAXIMUM RATINGS} \ (T_J = 25^{\circ}C \ unless \ otherwise \ noted)$

Rating	Symbol	Value	Unit
Drain-to-Source Voltage Internally Clamped	V_{DSS}	52–59	V
Gate-to-Source Voltage - Continuous	V _{GS}	±15	V
Drain Current - Continuous @ T_A = 25°C - Single Pulse (t_p = 10 μ s) (Note 1)	I _D	2.6 10	А
Total Power Dissipation @ T _A = 25°C (Note 1)	P _D	1.69	W
Operating and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C
Single Pulse Drain–to–Source Avalanche Energy (V _{DD} = 50 V, I _{D(pk)} = 1.17 A, V _{GS} = 10 V, L = 160 mH, R _G = 25 Ω)	E _{AS}	110	mJ
Load Dump Voltage (V_{GS} = 0 and 10 V, R_I = 2.0 Ω , R_L = 9.0 Ω , td = 400 ms)	V_{LD}	60	V
Thermal Resistance, Junction-to-Ambient (Note 1) Junction-to-Ambient (Note 2)	$R_{ hetaJA} \ R_{ hetaJA}$	74 169	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from Case for 10 Seconds	T _L	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- When surface mounted to a FR4 board using 1" pad size, (Cu area 1.127 in²).
 When surface mounted to a FR4 board using minimum recommended pad size, (Cu area 0.412 in²).

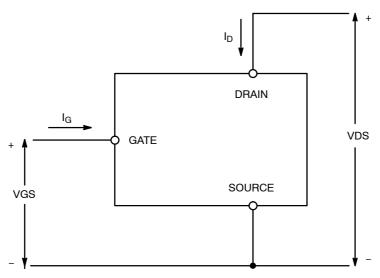


Figure 1. Voltage and Current Convention

$\textbf{MOSFET ELECTRICAL CHARACTERISTICS} \ (T_J = 25^{\circ}\text{C unless otherwise noted})$

Charac	Symbol	Min	Тур	Max	Unit		
OFF CHARACTERISTICS							
$\begin{array}{c} \text{Drain-to-Source Breakdown Voltage (N} \\ \text{(V}_{GS} = 0 \text{ V, I}_D = 1.0 \text{ mA, T}_J = 25^{\circ}\text{C)} \\ \text{(V}_{GS} = 0 \text{ V, I}_D = 1.0 \text{ mA, T}_J = -40^{\circ}\text{C} \\ \text{Temperature Coefficient (Negative)} \end{array}$	V _{(BR)DSS}	52 50.8	55 54 –9.3	59 59.5	V V mV/°C		
Zero Gate Voltage Drain Current $(V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V})$ $(V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^{\circ}\text{C})$	I _{DSS}			10 25	μΑ		
Gate-Body Leakage Current $(V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V})$ $(V_{GS} = \pm 14 \text{ V}, V_{DS} = 0 \text{ V})$	I _{GSS}		±35	±10	μΑ		
ON CHARACTERISTICS (Note 3)						•	
Gate Threshold Voltage (Note 3) $(V_{DS} = V_{GS}, I_D = 100 \mu A)$ Threshold Temperature Coefficient (Neg	V _{GS(th)}	1.1	1.5 -4.1	1.9	V mV/°C		
Static Drain-to-Source On-Resistance (Note 3) $(V_{GS} = 3.5 \text{ V}, I_D = 0.6 \text{ A})$ $(V_{GS} = 4.0 \text{ V}, I_D = 1.5 \text{ A})$ $(V_{GS} = 10 \text{ V}, I_D = 2.6 \text{ A})$		R _{DS(on)}		135 150 95	180 160 110	mΩ	
Forward Transconductance (Note 3) (V	_{OS} = 15 V, I _D = 2.6 A)	9 _{FS}		3.8		Mhos	
DYNAMIC CHARACTERISTICS							
Input Capacitance		C _{iss}		155		pF	
Output Capacitance	$V_{DS} = 35 \text{ V}, V_{GS} = 0 \text{ V},$ f = 10 kHz	C _{oss}		60			
Transfer Capacitance		C _{rss}		25			
Input Capacitance		C _{iss}		170		pF	
Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 10 kHz	C _{oss}		70			
Transfer Capacitance		C _{rss}		30			

^{3.} Pulse Test: Pulse Width \leq 300 $\mu s,$ Duty Cycle \leq 2%.

^{4.} Not subject to production testing.5. Switching characteristics are independent of operating junction temperatures.

MOSFET ELECTRICAL CHARACTERISTICS (T_{.1} = 25°C unless otherwise noted)

Charac	Symbol	Min	Тур	Max	Unit	
SWITCHING CHARACTERISTICS (No	ote 5)					
Turn-On Delay Time		t _{d(on)}		375		ns
Rise Time	V _{GS} = 4.5 V, V _{DD} = 40 V,	t _r		1525		
Turn-Off Delay Time	$I_D = 2.6 \text{ A}, R_D = 15.4 \Omega$	t _{d(off)}		1530		
Fall Time		t _f		1160		
Turn-On Delay Time		t _{d(on)}		325		ns
Rise Time	V _{GS} = 4.5 V, V _{DD} = 40 V,	t _r		1275		
Turn-Off Delay Time	$I_D = 1.0 \text{ A}, R_D = 40 \Omega$	t _{d(off)}		1860		
Fall Time		t _f		1150		
Turn-On Delay Time		t _{d(on)}		190		ns
Rise Time	V _{GS} = 10 V, V _{DD} = 15 V,	t _r		710		
Turn-Off Delay Time	$I_D = 2.6 \text{ A}, R_D = 5.8 \Omega$	t _{d(off)}		2220		
Fall Time		t _f		1180		
Gate Charge		Q _T		4.5		nC
	$V_{GS} = 4.5 \text{ V}, V_{DS} = 40 \text{ V},$ $I_{D} = 2.6 \text{ A (Note 3)}$	Q ₁		0.9]
	10 = 2.5 % (Note 3)	Q ₂		2.6		
Gate Charge		Q _T		3.9		nC
	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 1.5 \text{ A (Note 3)}$	Q ₁		1.0		
	10 = 1.0 % (Note 9)	Q ₂		1.7		
SOURCE-DRAIN DIODE CHARACTE	RISTICS	•	•			
Forward On-Voltage	I_S = 2.6 A, V_{GS} = 0 V (Note 3) I_S = 2.6 A, V_{GS} = 0 V, T_J = 125°C	V _{SD}		0.81 0.66	1.5	V
Reverse Recovery Time		t _{rr}		730		ns
	$I_S = 1.5 \text{ A}, V_{GS} = 0 \text{ V},$ $dI_S/dt = 100 \text{ A/}\mu\text{s} \text{ (Note 3)}$	t _a		200		
	αίζιαι = 100 / γμο (11010 0)	t _b		530		
Reverse Recovery Stored Charge		Q _{RR}		6.3		μC
ESD CHARACTERISTICS (Note 4)		•	•	•		
Electro-Static Discharge Capability	Human Body Model (HBM)	ESD	5000			V
	Machine Model (MM)		500			
	1					

^{3.} Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2%.

^{4.} Not subject to production testing.5. Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

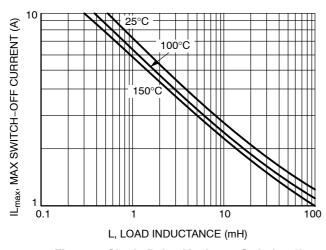


Figure 1. Single Pulse Maximum Switch-off Current vs. Load Inductance

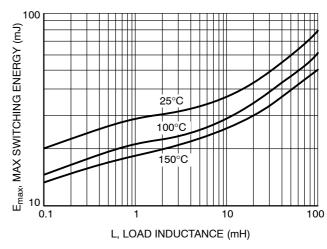


Figure 2. Single Pulse Maximum Switching Energy vs. Load Inductance

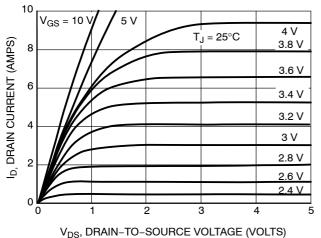


Figure 3. On-State Output Characteristics

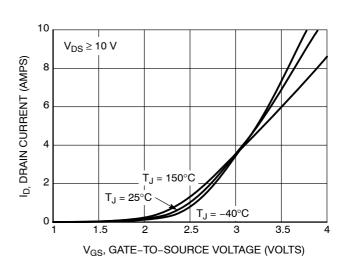


Figure 4. Transfer Characteristics

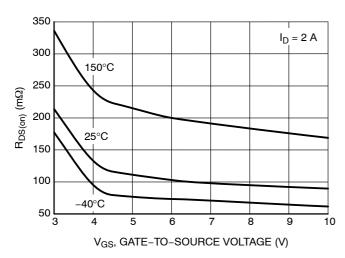


Figure 5. R_{DS(on)} vs. Gate-Source Voltage

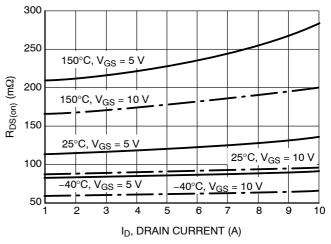


Figure 6. R_{DS(on)} vs. Drain Current

TYPICAL PERFORMANCE CURVES

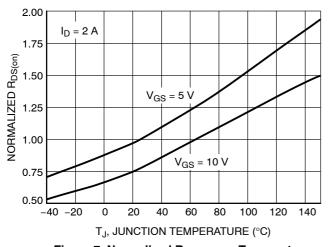


Figure 7. Normalized R_{DS(on)} vs. Temperature

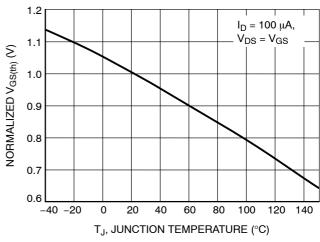


Figure 8. Normalized Threshold Voltage vs.
Temperature

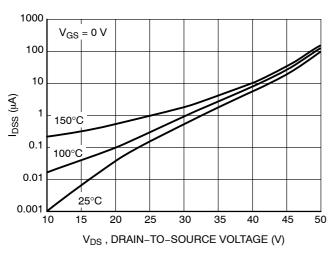


Figure 9. Drain-to-Source Leakage Current

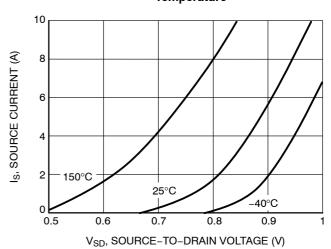


Figure 10. Source-Drain Diode Forward Characteristics

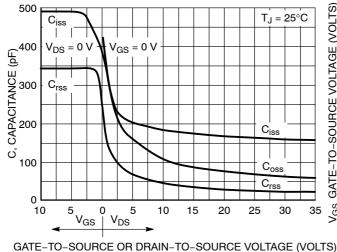


Figure 44 Oggazitance Variation

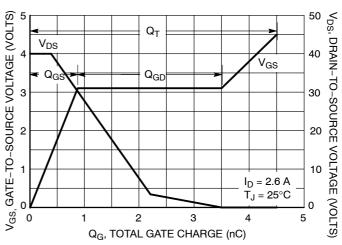


Figure 12. Gate-to-Source Voltage vs. Total Gate Charge

TYPICAL PERFORMANCE CURVES

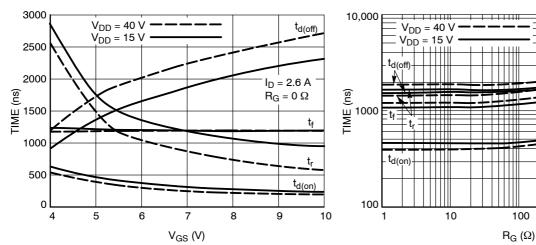


Figure 13. Resistive Load Switching Time vs.

Gate-Source Voltage

Figure 14. Resistive Load Switching Time vs. Gate Resistance ($V_{GS} = 5 \text{ V}, I_D = 2.6 \text{ A}$)

1000

10,000

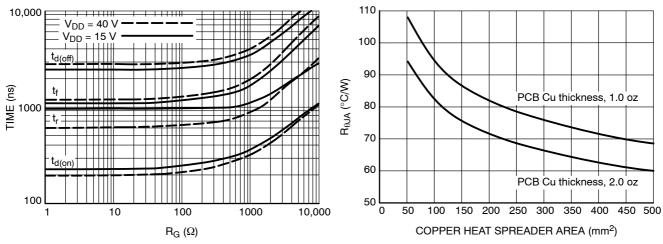


Figure 15. Resistive Load Switching Time vs. Gate Resistance (V_{GS} = 10 V, I_{D} = 2.6 A)

Figure 16. $R_{\theta JA}$ vs. Copper Area

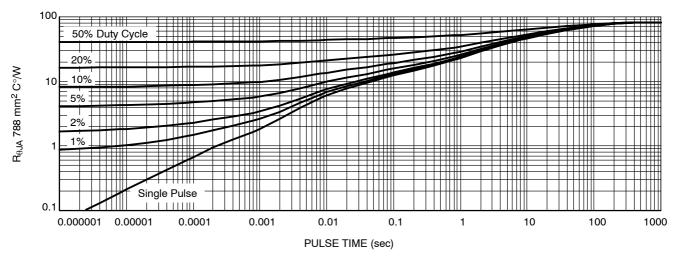
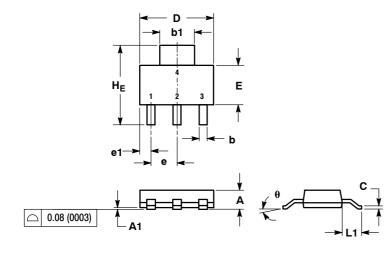


Figure 17. Transient Thermal Resistance

PACKAGE DIMENSIONS

SOT-223 (TO-261) CASE 318E-04 ISSUE L



NOTES:

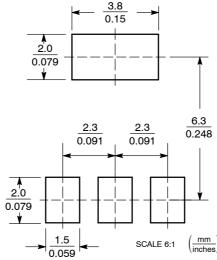
- DIMENSIONING AND TOLERANCING PER ANSI
- Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

	М	MILLIMETERS			INCHES	
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	1.50	1.63	1.75	0.060	0.064	0.068
A1	0.02	0.06	0.10	0.001	0.002	0.004
b	0.60	0.75	0.89	0.024	0.030	0.035
b1	2.90	3.06	3.20	0.115	0.121	0.126
С	0.24	0.29	0.35	0.009	0.012	0.014
D	6.30	6.50	6.70	0.249	0.256	0.263
E	3.30	3.50	3.70	0.130	0.138	0.145
е	2.20	2.30	2.40	0.087	0.091	0.094
e1	0.85	0.94	1.05	0.033	0.037	0.041
L1	1.50	1.75	2.00	0.060	0.069	0.078
HE	6.70	7.00	7.30	0.264	0.276	0.287
θ	0°	-	10°	0°	-	10°

STYLE 3:

- PIN 1. GATE
- 2. DRAIN SOURCE
- 4. DRAIN

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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